

In re Patent application of

Ji-Soo KIM et al.

Group Art Unit 2881

Serial No. 10/673,581

Examiner Kalimah FERNANDEZ

Filed 30 September 2003

METHOD OF DETERMINING WHETHER A CONDUCTIVE LAYER OF A SEMICONDUCTOR DEVICE IS EXPOSED THROUGH A CONTACT HOLE

AMENDMENT UNDER 37 C.F.R. § 1.112

U.S. Patent and Trademark Office Customer Window, **Mail Stop Amendment** Randolph Building 401 Dulany Street Alexandria, VA 22314

Sir:

In response to the Office Action of 19 October 2004, the period for response to which is hereby being extended by the accompanying Petition and Petition Fee through 19 February 2005, reexamination and reconsideration of the above-referenced U.S. patent application are respectfully requested in view of the following Remarks.

Remarks begin on page 2 of this paper.